

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/065,816	HARDWICKE ET AL.	
Examiner		Art Unit		Page 1 of 1
Gail Verbitsky		2859		

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C	US-6568848	05-2003	Chapman et al.	374/155
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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	Thin film temperature sensors for gas turbine engines: Problems and prospects. Article by Budhani et al. 1986.	
V	News Monitor. Measure High Temperature Changes in Microseconds. abstract by Kreider. no date.	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.